Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/724,846	HOSHINO ET AL.	
Examiner	Art Unit	
Ly T. TRAN	2853	

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Class	Subclass	Date	Examiner
347	102	6/23/2006	LT

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			
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